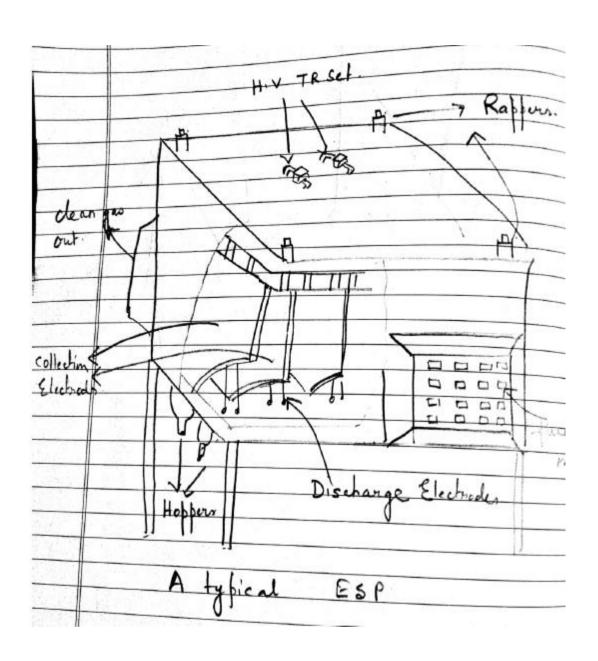
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Electrostatic Precipitation .. 8.5. Ps have been used for over particulate have cement femperature that produce All ESPs contain six essential components à-1) Discharge Electrodes o impart lin a gas to are usually small-dia vertically in the I ESP on sugrid mast . They can framels plates with I needle lection Electrodes o collect the charged. either tubes be and they have a discharge electrodes. also called transformer. , one used to the strength and collection electrodes. are mechanismos that provide on on shock to both the ection and discharge electrodes.

	The vibration shock causes the particles attacked to there electrodes to fall into hoppers.
	the dell into hopeus
	True etections to face
A-520	Hopers are him used to collect and temporar
	stone the particles gremoved deving grapping. It.
	Hoppers are bins used to collect and temporous, store the particles removed deving reapping. This are located at the bottom of an Esp. I sp.
	ACCOUNT OF THE PROPERTY OF THE
	Shell encloses the electrodes and supports the
1500	precipitation components in a suigno frame to mainles
3,455	proper electrode alignment and configuration. The shell is covered with insulation to conserve
	shell is covered with insulation to conserve
	heat and brevent corrosion. The outer shell
	wall is usually made of steel.
	FSP Sucher Objection ? The bar
	ESP System Operation: The ban'c process underlying ESP operation is that pollutant
STATE OF STA	me bicle of Air a god the
	charged (usually with a negative charge) which causes them to onigonate toward
等外面。	which causes I them to enjoyate to the
CONTRACT (	and attach Thempelves to collection by
Wiles !	ubes that are oblesitely charge of The collection
5555	and discharge electroly and IP. 1111
1	Causes the particles attached to the electrods
y the last	causes the particles attached to the electrons
湖 公司	to fall into a collection hopber.
	A high voltage direct awarent is abblice
	to a discharge wine (electrode) negatively
	changing it. I Voltage to the wine is
	more shigh until a corona is broduced are
-	the wine.
	As the particle lader flue gases
	passes through the corroma the particles contain
and tall the	Scanned by CamScanner

What is sectionalization?

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B	ut in the downstre	sparking, so lower crows
110	ading is usually lig	the high sower would
b	man and an analysis of	TO A POST OF THE PROPERTY OF THE PARTY OF TH
	Marie Con C	1- K pet were un
0	laceral Libra II box	fo avoid excessive
6	sparking thus e	ficient of entire unit
(	would of be nede	iced.
	Types of ESPs:-	
2	· Plake wire ESP · Flat blate ESP	6. Cold side ESP.
3	Tubular Esp.	8 Dry ESP
4	· Single stope ESP. · Two stope ESP	9. WILL ESP.
100		

7 Lo	A Desire Land	The second secon	
1 0	w operating cost.	14 FT 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	
7 Per	sperature steels	ibility in design.	th'cle.
-1 Al	ility to handle	vedu large 1	nation
I	is advantages of	F5100-	
コト	igh capital cos	t Cexpensive to purchase	2 install

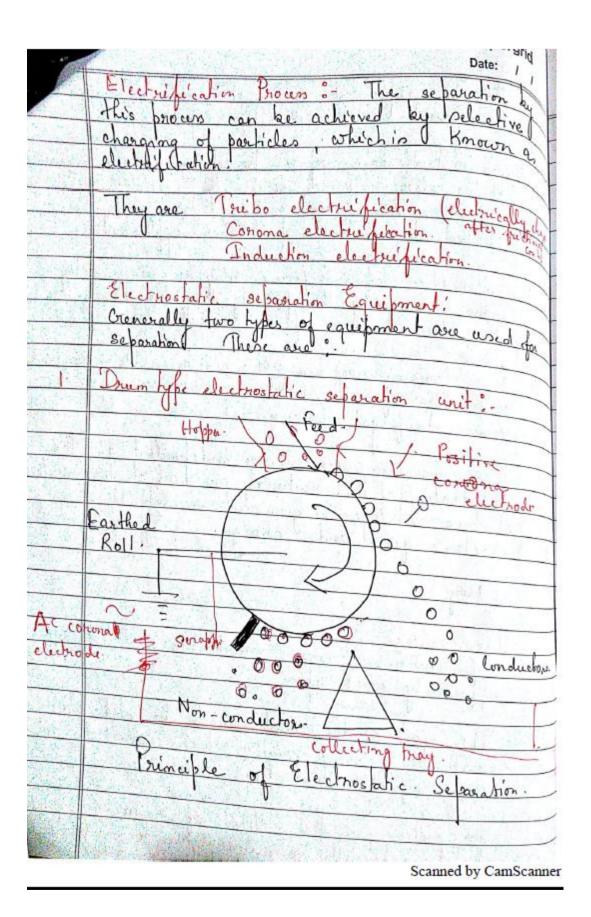
	Date:
Musible i e once installed it	in not easy to
1 feet 1 L another places.	0
install it to son particles wi	IP 1.1
failure to obvide on santicles with	The high
alestucal rehistrity.	
Efficiency curve for ESPs.	
Efficiency Conta	
100	- The state of the
996	
2 80	
E 40	
\$ 60	
3 50	
3 100 200 300 400 500	600-
	4
corona bower satio, W/1000	Cfm.
T 540	1 1 0
Typical equiviency of an ESP as	a function of
corone power ranh	
Power Consumed in Wal	4
	est per minute
air flow in cubic q	(cfm).

1b Electrostatis separator

	lectrostatic Separation.  lectrostatic separation is one of those important
411111111111111111111111111111111111111	
-	proporty of mineral surface is used selection of to separate out denirable mineral from of
1	undesirable minerals.
7	Electrostatic forces are generated by the action of an electric field on a charged particle.
1	In an Es process one needs a source of
1.	field and a proces by which the
1	individual particles are charged electrically
+	tactors have significant effect on the prour
1	1. Intensity of declaric field.
0	2. Particle size.
1	3. Relative humidin
+	4. Pemporature of the particle bed
-	5 01
1	anier destrode destance
1	Advantages.
	) Electrostatic gonces work on the particles
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Date: only, they do not barticle to be separated in which the go llow application E.S fonces may polarity changing amanged onceb gravitational imitation marks mass work makerial Compaination the action , especially a mineral one to middle particles on grayments.

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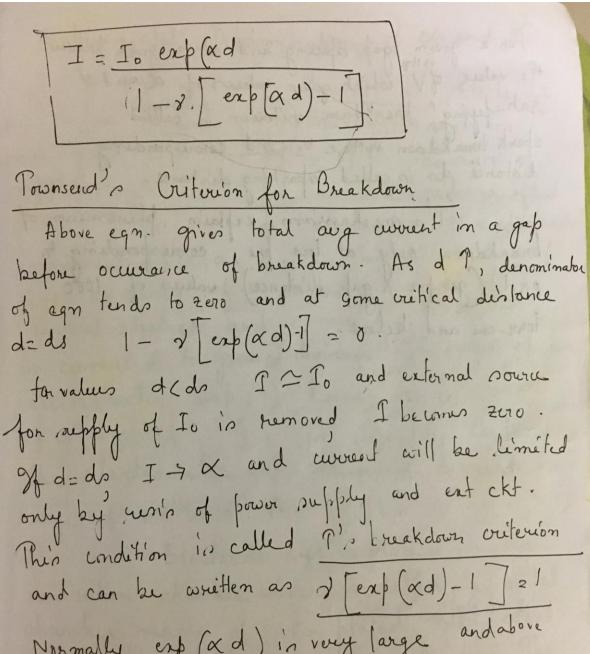


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Ref to figo, let us assume that no es are emitted from Cathode. When one e collide a neutral particle, a tre ion and an a arel This is called lone zing collision to het & be any no of ionizing collisions made by an e / con travel in the direction of the fld (x depends on gas pre p and E/P. and called P's first ionization coeff). How distance & from cathode, let no of election be no . When there no es travel a further distance of dx, they give ness to donada & At x=0, nx=no Also done = Long or on = no exp(Kz) & Then no of a reaching anode (2=d) nd = no exp (ax) - (3) Number of new es created, on any by each e is nd-no = exp(xd) -1

. Any current in gap, which is equal to no. of es travelling per second will be. where Io is imitial awarent at the cathode. Current Growth In The Presence of 2ndary Processes Single avalanche process becomes complete when initial sets les reaches anode. Since amplification of 2s Text (xd) is occurring in fld, probability of additional new es being liberated in gap by other mechanisms 1 and these new es create further avalanches. Other mechanisms are ) the ion liberaled may have sufficient energy to cause liberations of es from the cathode when they impinge on it by Excited mots or atoms in avalanches may with photo- emission. in) Meta stable particle may diffuse back couring e emission.



Normally exp (xd) is very large and above egm. reduces to | yexp(xd) = 1

1-

e sproduced by these enussion. At 2ndary ionization coeff & is defined as not number of 2ndary es produced by per incident tre ions photon, excited particle on metastable particle and total value of & is num of individua coeffs due to 3 diff processes.  $y=y_1+y_2+y_3$ 7 -7 T's 2ndary ionization coeff and function of P and E/P following I's procedure of wevent growth let us assume, no! = no. of 2ndary es produced due to 2ndary processes no" - total no of es leaving cathode  $m_0 = m_0 + m_0$ No tal mo of es n reaching ande n=no"exp(ad = (no+no") exp(ad and mo' = 2 (mo + mo) Eliminating no n= no exp(a

#### 2b Limitation In Townsend's Mechanism

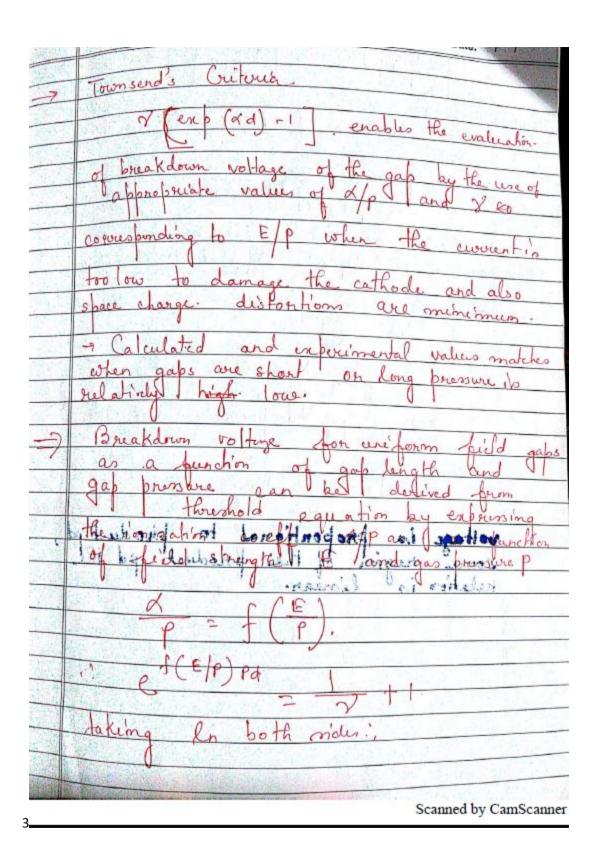
• Townsend mechanism when applied to breakdown at atmospheric pressure was found to have certain drawbacks.

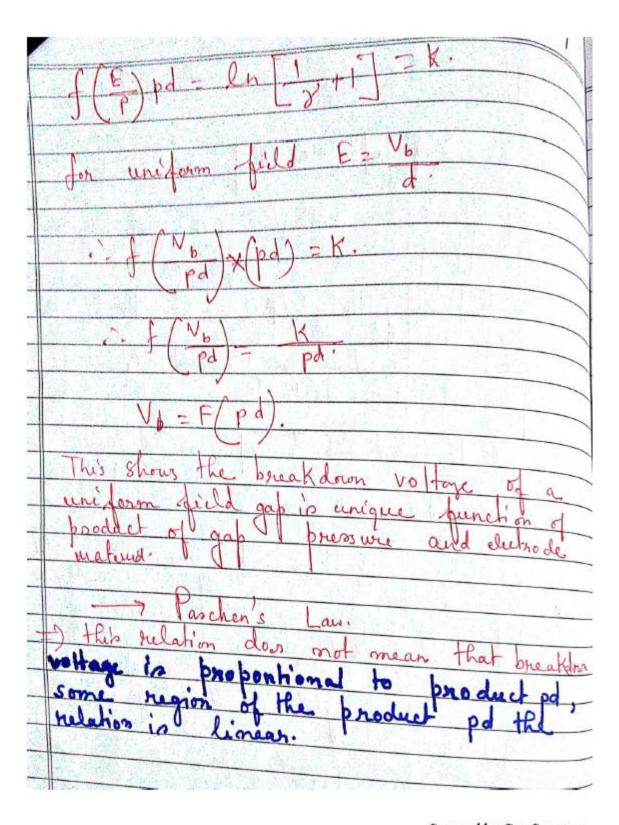
• A) according to the Townsend theory, current growth

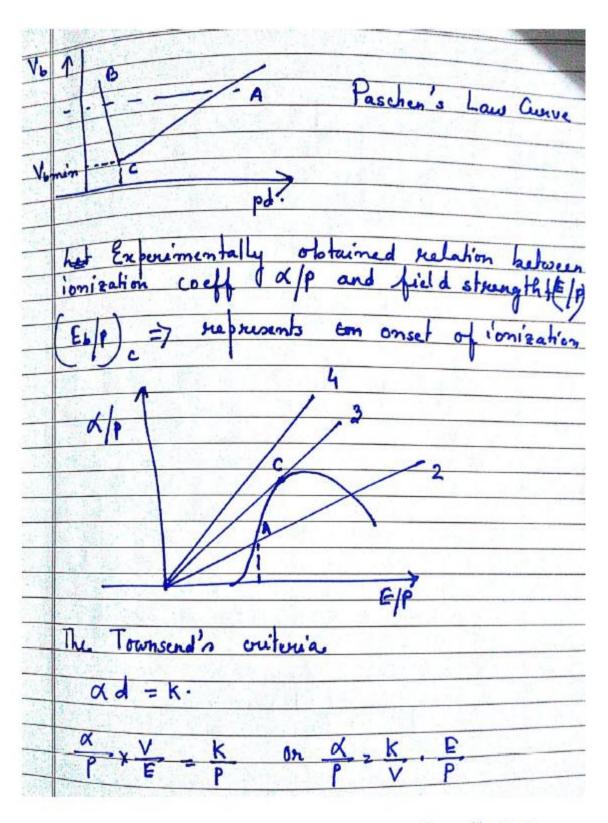
occurs as a result of ionization processes only. But in practice, breakdown voltages were found to depend on the gas pressure and the geometry of the gap.

- B) Mechanism predicts time lags of the order of 10-5S, while in actual practice breakdown was observed to occur at very short times of the order of 10-8S.
- C) Townsend mechanism predicts a very diffused form of discharge, in actual practice, discharges were found to be filamentary and irregular.

The Townsend mechanism failed to explain all these observed phenomena and as a result, around 1940, Raether and, Meek and Loeb independently proposed the **Streamer theory**.



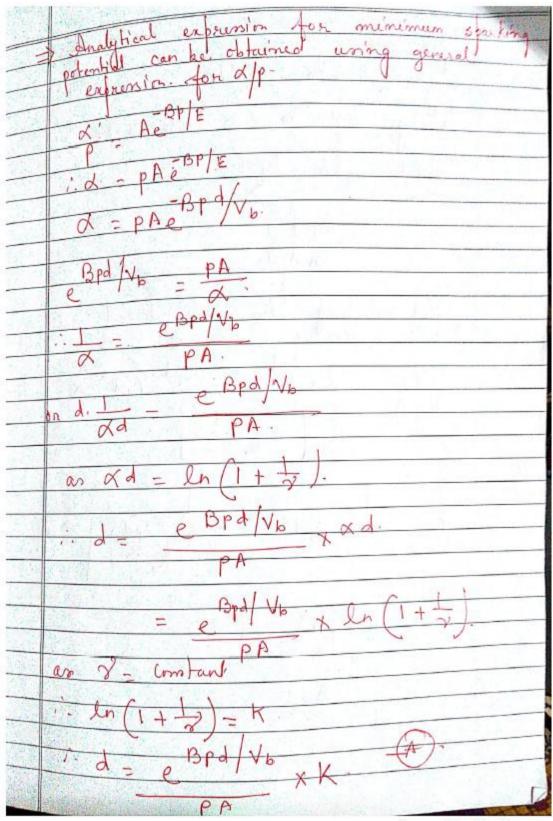




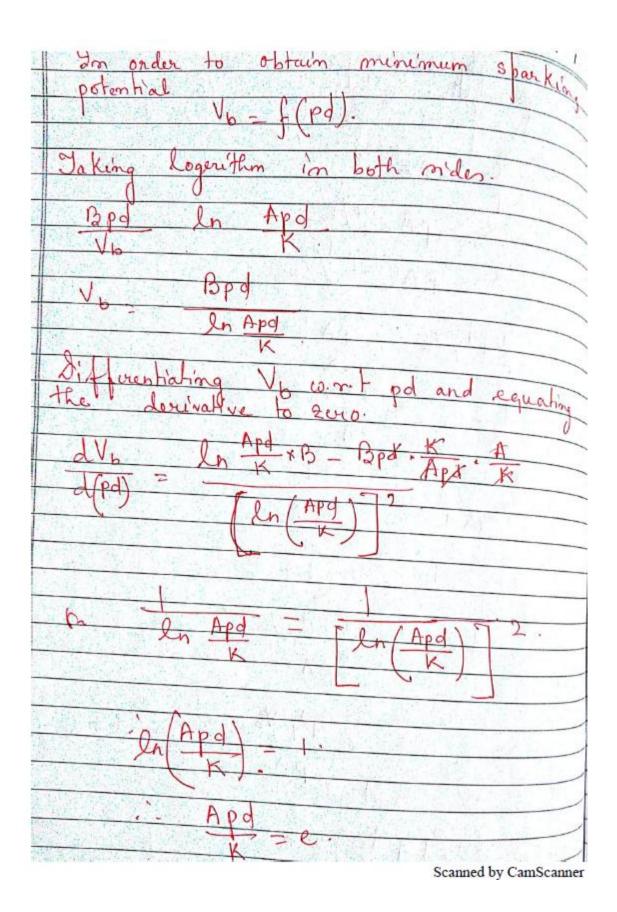
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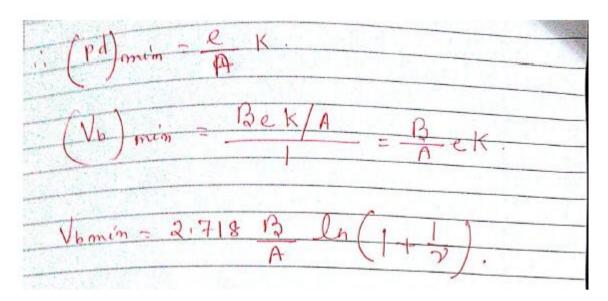
This is equation to a straight line, with slope equal to K/V, depending upon the value of R
equation 1 1 10 10 10 10 10 10 10 10 10 10 10 10
This I to K/V depending upon the value of 18
The equal 10
1210
111 he the voltage smaller slope
Higher III is hard imprised in augus of
this line will imposed ton each at
Slope equal frequency of the voltage smaller slope  Higher the voltage smaller slope  This line will intrused ionization curve at two points. A and B.
two pomis
to must be two breakdown voltages at
of there musi
1 constant pressure pone corces ponding to
11 value of gab length le hither E (F=1)
There must be two breakdown voltages at a constant pressure P one conversionding to small value of gap length: i've higher E (F=Y) i've point B
Tie bont 12
I I I longer and longth i'm smaller
other to the strain
FAM E/p ice point A.
7 other to the longer gap length i've smaller E or E/p ive point A.
At low values of voltage. V, the slope of the straight line is large.
At low values of Noltage. V The stope of
atraight like is large
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no intersection between line and curvet.
no intersection between time and active
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This means no break about
Small nottages below Parcher's minimum
e li I I I por police or police
isverspective of the value of pd.
= Point C on the curve indicates the lowest
breakdown voltage on minimum sparing
Potential.
46 W 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
3 Shock was voltime corner ponding to boints
Spark over voltage corner penalification
A B C are shown in previous figure.
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## 4.a THERMAL BREAKDOWN

- The breakdown voltage of a solid dielectric should increase with its thickness.
- This is true only up to a certain thickness above which the heat generated in the dielectric due to the flow of current determines the conduction.
- When an electric field is applied to a dielectric, conduction current, however small it may be, flows through the material.
- The current heats up the specimen and the temperature rises.
- The heat generated is transferred to the surrounding medium by conduction through the solid dielectric and by radiation from its outer surfaces.
- Equilibrium is reached when the heat used to raise the temperature of the dielectric, plus the heat radiated out, equals the heat generated. The heat generated under d.c. stress *E is given as*

$$W_{d.c.} = E^2 \sigma$$
 W/cm<sup>3</sup>

- where, δ is the d.c. conductivity of the specimen.
- Under a.c. fields, the heat generated

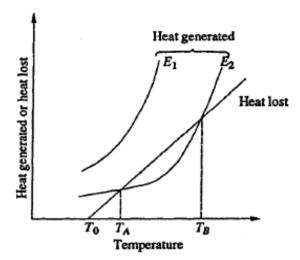
$$W_{\text{a.c.}} = \frac{E^2 f \varepsilon_r \tan \delta}{1.8 \times 10^{12}} \quad \text{W/cm}^3$$

- where, *f*= frequency in Hz,
- $\delta$ = loss angle of the dielectric material, and

- E- rms value.
- The heat dissipated  $(W_T)$  is given by

$$W_T = C_V \frac{dT}{dt} + \text{div}(K \text{ grad } T)$$

- where,  $C_V$ = specific heat of the specimen,
- T= temperature of the specimen,
- K = thermal conductivity of the specimen, and
- t = time over which the heat is dissipated.
- Equilibrium is reached when the heat generated (Wa.c.or Wd.c.) becomes equal to Equilibrium is reached when the heat generated Wa.c.or Wd.c becomes equal to the heat dissipated (WT).
- In actual practice there is always some heat that is radiated out).
- Breakdown occurs when Wd.c. or Wa.c. exceeds WT.
- The thermal instability condition is shown in Fig.
- Here, the heat lost is shown by a straight line
- the heat generated at fields E1 and E2 are shown by separate curves.
- At field EI breakdown occurs both at temperatures TA and TB
- In the temperature region of TA and TB heat generated is less than the heat lost for the field E2 the breakdown will not occur.
- This is of great importance to practising engineers, as most of the insulation failures in high voltage power apparatus occur due to thermal breakdown.
- Thermal breakdown sets up an upper limit for increasing the breakdown voltage when the thickness of the insulation is increased.
- For a given loss angle and applied stress, the heat generated is proportional to the frequency and hence thermal breakdown is more serious at high frequencies.



- It can be seen
- since the power loss under a.c. fields is higher, the heat generation is also high, and hence the thermal breakdown stresses are lower under a.c. conditions than under d.c. conditions.

#### 4b ELECTROMECHANICAL BREAKDOWN

When solid dielectrics are subjected to high electric fields, failure occurs due

to electrostatic compressive forces which can exceed the mechanical compressive strength.

If the thickness of the specimen is 4\$ and is compressed to a thickness d under an applied voltage V, then the electrically developed compressive stress is in equilibrium

$$\varepsilon_0 \, \varepsilon_r \, \frac{V^2}{2d^2} = Y \ln \left[ \frac{d_0}{d} \right]$$

where Y is the Young's modulus.

Usually, mechanical instability occurs when

$$V^2 = d^2 \left[ \frac{2Y}{\varepsilon_0 \, \varepsilon_r} \right] \ln \left[ \frac{d_0}{d} \right]$$

Substituting this in Equation the highest apparent electric stress before breakdown,

# $d/d_0 = 0.6$ or $d_0/d = 1.67$

- The above equation is only approximate as Y depends on the mechanical stress.
- When the material is subjected to high stresses the theory of elasticity does not hold good, and plastic deformation has to be considered

$$E_{\text{max}} = \frac{V}{d_0} = 0.6 \left[ \frac{Y}{\varepsilon_0 \, \varepsilon_r} \right]^{\frac{1}{2}}$$

## 5. Suspended Particle Theory

- In commercial liquids, the presence of solid impurities cannot be avoided.
- These impurities will be present as fibres or as dispersed solid particles.
- The permittivity of these particles (ε1) will be different from the permittivity of the liquid (ε2).
- If we consider these impurities to be spherical particles of radius r, and if the applied field is E, then the particles experience a force F, where

$$F = r^3 \frac{\varepsilon_1 - \varepsilon_2}{\varepsilon_1 + 2\varepsilon_2} E \cdot \frac{dE}{dx}$$

- and this force is directed towards a place of higher stress if  $\varepsilon 1 > \varepsilon 2$  and towards a place of lower stress if  $\varepsilon 1 < \varepsilon 2$  when  $\varepsilon 1$  is the permittivity of gas bubbles.
- The force given above increases as the permittivity of the suspended particles ( $\epsilon 1$ ) increases. If  $\epsilon 1 \to \infty$

$$F = r^3 \frac{1 - \epsilon_2 / \epsilon_1}{1 + 2\epsilon_2 / \epsilon_1} E \frac{dE}{dx}$$

Let 
$$\varepsilon_1 \rightarrow \infty$$

$$F = r^3 E \cdot \frac{dE}{dx}$$

- Force will tend the particle to move towards the strongest region of the field.
- In a uniform electric field which usually can be developed by a small sphere gap, the field is the strongest in the uniform field region. Here dE/dx → 0 so that the force on the particle is zero and the particle remains in equilibrium.
- Particles will be dragged into the uniform field region.
- Permittivity of the particles is higher than that of the liquid, the presence of particle in the uniform field region will cause flux concentration at its surface.
- Other particles if present will be attracted towards the higher flux concentration.
- The movement of the particle under the influence of electric field is opposed by the viscous force posed by the liquid and since the particles are moving into the region of high stress, diffusion must also be taken into account.
- We know that the viscous force is given by (Stoke's relation)  $FV = 6\pi nrv$  where  $\eta$  is the viscosity of liquid, r the raidus of the particle and v the velocity of the particle.
- Equating the electrical force with the viscous force we have

$$6\pi\eta rv = r^3 E \frac{dE}{dx}$$
 or  $v = \frac{r^2 E}{6\pi\eta} \frac{dE}{dx}$ 

However, if the diffusion process is included, the drift velocity due to diffusion will be given by

$$v_d = -\frac{D}{N}\frac{dN}{dx} = -\frac{KT}{6\pi\eta r}\frac{dN}{Ndx}$$

where  $D = KT/6\pi\eta r$  a relation known as Stokes-Einstein relation. Here K is Boltzmann's constant and T the absolute temperature.

At any instant of time, the particle should have one velocity and, therefore, equation

$$v = vd$$

We have

$$-\frac{KT}{6\pi\eta r} \cdot \frac{dN}{Ndx} = \frac{r^2 E}{6\pi\eta} \cdot \frac{dE}{dx}$$
$$\frac{KT}{r} \frac{dN}{N} = -r^2 E dE$$
$$\frac{KT}{r} \ln N = -\frac{r^2 E^2}{2}$$

- It is clear that the breakdown strength *E* depends upon the concentration of particles *N*, radius *r* of particle, viscosity η of liquid and temperature *T* of the liquid.
- It has been found that liquid with solid impurities has lower dielectric strength as compared to its pure form.
- larger the size of the particles impurity the lower the overall dielectric strength of the liquid containing the impurity.
- If there is only a single conducting particle between the electrodes, it will give rise to local field enhancement depending on its shape.
- If this field exceeds the breakdown strength of the liquid, local breakdown will occur near the particle, and this will result

in the formation of gas bubbles which may lead to the breakdown of the liquid.

- The values of the breakdown strength of liquids containing solid impurities was found to be much less than the values for pure liquids.
- The impurity particles reduce the breakdown strength, and it was also observed that the larger the size of the particles the lower were the breakdown strengths
- Cavitation and the Bubble Theory
- experimentally observed that in many liquids, the breakdown strength depends

strongly on the applied hydrostatic pressure.

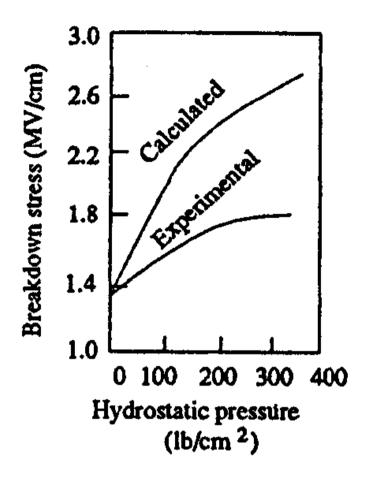
suggesting that a change of phase of the medium is involved in the breakdown process, which means kind of **vapour bubble** formed is responsible for breakdown.

The following processes are responsible for **formation of the vapour bubbles**:

- (a) Gas pockets at the surfaces of the electrodes;
- (b) electrostatic repulsive forces between space charges which may be sufficient to overcome the surface tension;
- (c) gaseous products due to the dissociation of liquid molecules by electron collisions
- (d) vaporizations of the liquid by corona type discharge from sharp points and irregularities on the electrode surfaces.
- Once a bubble is formed it will elongate in the direction of the electric field under the influence of electrostatic forces.
- The volume of the bubble remains constant during elongation.
- Breakdown occurs when the voltage drop along the length of the bubble becomes equal to the minimum value on the Paschen's curve
- The breakdown field is given as

$$E_0 = \frac{1}{(\varepsilon_1 - \varepsilon_2)} \left[ \frac{2\pi\sigma(2\varepsilon_1 + \varepsilon_2)}{r} \left\{ \frac{\pi}{4} \sqrt{\left(\frac{V_b}{2rE_0}\right)} - 1 \right\} \right]^{\frac{1}{2}}$$

- $\varepsilon$  1 is the permittivity of the liquid,
- ε2 is the permittivity of the gas bubble,
- r is the initial radius of the bubble assumed as a sphere
- Vb is the voltage drop in the bubble (corresponding to minimum on the
- Paschen's curve).
- From this equation, it can be seen that the breakdown strength depends on the initial size of
  the bubble which in turn is influenced by the hydrostatic pressure and temperature of the
  liquid.
- This theory does not take into account the production of the initial bubble and hence the results given by this theory do not agree well with the experimental results



6a

When a solid dielectric subjected to electrical stresses for a long time fails, normally two kinds of visible markings are observed on the dielectric materials. They are:

- (a) the presence of a conducting path across the surface of the insulation;
- (b) a mechanism whereby leakage current passes through the conducting path

finally leading to the formation of a spark.

Insulation deterioration occurs as a result of these sparks.

The spreading of spark channels during *tracking, in the form of the branches of a* tree is called **treeing**.

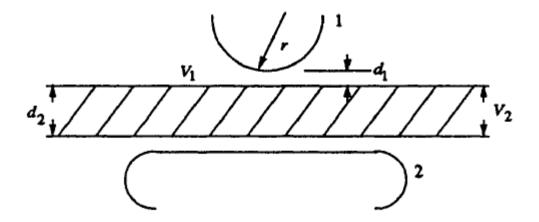
- Consider a system of a solid dielectric having a conducting film and two electrodes on its surface.
- In practice, the conducting film very often is formed due to moisture.
- On application of voltage, the film starts conducting, resulting in generation of heat, and the surface starts becoming dry.
- The conducting film becomes separate due to drying, and so sparks are drawn damaging the dielectric surface.

With organic insulating materials such as paper and bakelite, the dielectric carbonizes at the region of sparking, and the carbonized regions act as permanent conducting channels resulting in increased stress over the rest of the region.

This is a cumulative process, and insulation failure occurs when carbonized tracks bridge the distance between the electrodes.

This phenomena, called **tracking** is common between layers of bakelite, paper and similar dielectrics built of laminates

- Treeing occurs due to the erosion of material at the tips of the spark.
- Erosion results in the roughening of the surfaces, and hence becomes a source of dirt and contamination.
- This causes increased conductivity resulting either in the formation of a conducting path bridging the electrodes or in a mechanical failure of the dielectric.



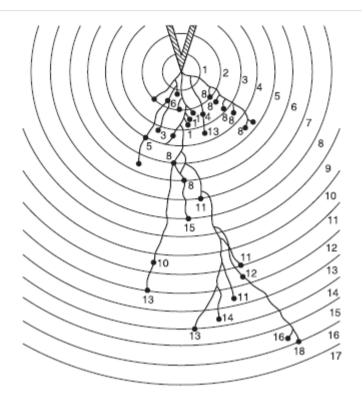
- Arrangement for study of treeing phenomena. 1 and 2 are electrodes
- When a dielectric material lies between two electrodes as shown in Fig. there is a possibility for two different dielectric media, the air and the dielectric, to come in series.

- The voltages across the two media are as shown (V1 across the air gap, and V2 across the dielectric).
- The voltage V1 across the air gap is given as,

$$V_1 = \frac{V d_1}{d_1 + \left(\frac{\varepsilon_1}{\varepsilon_2}\right) d_2}$$

where V is the applied voltage.

- Since  $\varepsilon 2 > \varepsilon 1$ , most of the voltage appears across **d1** the air gap.
- Sparking will occur in the air gap and, charge accumulation takes place on the surface of the insulation.
- Sometimes the spark erodes the surface of the insulation.
- As time passes, breakdown channels spread through the insulation in an irregular "tree" like fashion leading to the formation of conducting channels.
- This kind of channelling is called treeing
- Usually, tracking occurs even at very low voltages of the order of about 100 V, whereas treeing requires high voltage.
- For testing of tracking, low and medium voltage tracking tests are specified.
- These tests are done at low voltages but for times of about 100 hr or more.
- The insulation should not fail.
- Sometimes the tests are done using 5 to 10 kV with shorter durations of 4 to 6 hr.
- The numerical value of voltage that initiates or causes the formation of a track is called the "tracking index" and this is used to qualify the surface properties of dielectric materials.
- Treeing can be prevented by having clean, dry, and undamaged surfaces and a clean environment.
- The materials chosen should be resistant to tracking.
- Sometimes moisture repellant greases are used.
- But this needs frequent cleaning and regreasing.
- Increasing creepage distances should prevent tracking, but in practice the presence of moisture films defeat the purpose.
- Usually, treeing phenomena is observed in capacitors and cables.



6b

- It has been recognized that one process that gives high breakdown strength to a gas is the electron attachment in which free electrons get attached to neutral atoms or molecules to form negative ions.
- Since negative ions like positive ions are too massive to produce ionization due to collisions, attachment represents an effective way of removing electrons which otherwise would have led to current growth and breakdown at low voltages.
- The gases in which attachment plays an active role are called **electronegative gases.**
- The most common attachment processes encountered in gases are
- (a) the direct attachment in which an electron directly attaches to form a negative ion,
- (b) the dissociative attachment in which the gas molecules split into their constituent atoms and the electronegative atom forms a negative ion.
- These processes may be symbolically represented as:
- (a) Direct attachment

$$AB + e \longrightarrow AB^-$$
.

• (b) Dissociative attachment

 $AB + e \longrightarrow A + B^-$ 

- A simple gas of this type is oxygen. Other gases are sulphur hexafluoride, freon, carbon dioxide, and fluorocarbons.
- In these gases, 'A" is usually sulphur or carbon atom, and 'B\* is oxygen atom or one of the halogen atoms or molecules.
- With such gases, the Townsend current growth equation is modified to include ionization and attachment
- An attachment coefficient (η) is defined, as the number of attaching collisions made by one electron drifting one centimetre in the direction of the field.
- Under these conditions the current reaching the anode, can be written as:

$$I = I_0 \frac{\left[\left[\alpha/(\alpha - \eta)\right] \exp(\alpha - \eta)d\right] - \left[\eta/(\alpha - \eta)\right]}{1 - \left\{\gamma \frac{\alpha}{(\alpha - \eta)}\left[\left\{\exp(\alpha - \eta)d\right\} - 1\right]\right\}}$$

 The Townsend breakdown criterion for attaching gases can also be deduced by equating the denominator to zero:

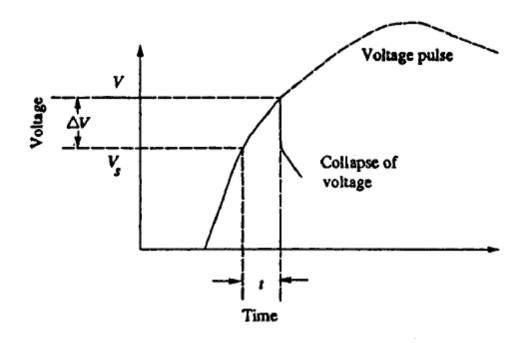
$$\gamma \frac{\alpha}{(\alpha - \eta)} \left[ \exp(\alpha - \eta) d - 1 \right] = 1$$

- This shows that for  $\eta < \alpha$  breakdown is always possible irrespective of the values of  $\alpha$ ,  $\eta$ ,  $\gamma$
- If on the other hand,  $\eta > \alpha$  Eq approaches an asymptotic form with increasing value of d,

$$\gamma \frac{\alpha}{(\alpha - \eta)} = 1$$
; or  $\alpha = \frac{\eta}{(1 - \gamma)}$ 

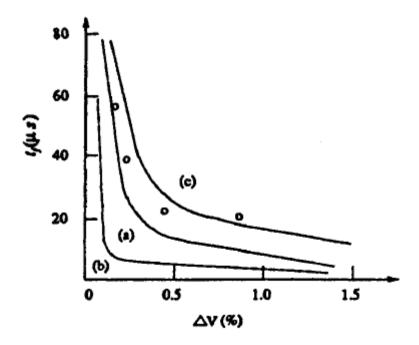
• This condition puts a limit for E/p below which no breakdown is possible irrespective of the value of d, and the limit value is called the **critical E/p**. Critical E/p for SF6 is 117 V cm<sup>-1</sup> torr<sup>-1</sup>, and for CCl2F2 it is 121 V cm<sup>-1</sup> torr<sup>-1</sup> (both at 20°C).

- The mechanism of spark breakdown is considered as a function of ionization processes under uniform field conditions.
  - But in practical engineering designs, the breakdown due to rapidly changing voltages or impulse voltages is of great importance.
- Actually, there is a time difference between the application of a voltage sufficient to cause breakdown and the occurrence of breakdown itself.
- This time difference is called the time lag.
- The Townsend criterion for breakdown is satisfied, only if at least one election is present in the gap between the electrodes.
- In the case of applied d.c. or slowly varying (50 Hz a.c) voltages, there is no difficulty in satisfying this condition.
- With rapidly varying voltages of short duration (=10-6 s), the initiatory electron may not be present in the gap.
- In the absence of such an electron breakdown cannot occur.
- The time t which lapses between the application of the voltage sufficient to cause breakdown and the appearance of the initiating electron is called a statistical time lag (ts)of the gap.
- The appearance of electrons is usually statistically distributed.
- After the appearance of the electron, a time *tt is required for the ionization processes to* develop fully to cause the breakdown of the gap
- this time is called the **formative time lag** (tt).
- The total time ts + tt=t is called the total time lag.
- Time lags are of considerable practical importance.
- For breakdown to occur the applied voltage *V* should be greater than the static breakdown voltage *Vs* as shown in Fig.
- The difference in voltage  $\Delta V = V$  Vs is called the **overvoltage**
- ratio V/Vs is called the **impulse ratio**.



Breakdown on the front of the applied impulse voltage wave

• The variation of tt with overvoltage ( $\Delta V$ ) is shown in Fig.



 The voltage which has to be applied to a test object under specified conditions in a withstand test is called the withstand voltage

#### 7b Hundred Per Cent Flashover Voltage

The voltage that causes a flashover at each of its applications under specified conditions when applied to test objects is specified as **hundred per cent flashover voltage**.

## 7c Fifty Per Cent Flashover Voltage

- This is the voltage which has a probability of **50% flashover**, when applied to a test object.
- This is normally applied in impulse tests in which the loss of insulation strength is temporary

## 7d Disruptive Discharge Voltage

- This is defined as the voltage which produces the loss of dielectric strength of an insulation.
- It is that voltage at which the electrical stress in the insulation causes a failure which includes the collapse of voltage and passage of current.
- In solids, this causes a permanent loss of strength.
- In liquids or gases only temporary loss may be caused.
- When a discharge takes place between two electrodes in a gas or a liquid or over a solid surface in air, it is called **fiashover**.
- If the discharge occurs through a solid insulation it is called **puncture**.

## 7e Creepage Distance

It is the shortest distance on the contour of the external surface of the insulator unit or between two metal fittings on the insulator.

Solution: 1st Set. Since there is gradual increase in current upto gap distance of 3 mm, slope between any two points

$$\left(\frac{\ln I/I_0}{x}\right)$$

will give us the value of  $\alpha$ .

Let us take gap distances of 2 and 2.5 mm.

The respective  $\ln I/I_0$  are

$$\ln\left(\frac{1.5\times10^{-12}}{6\times10^{-14}}\right) = 3.2188$$

and

$$\ln\left(\frac{1.5\times10^{-12}}{6\times10^{-14}}\right) = 4.5362$$

$$=\frac{4.5362-3.2188}{0.05}=26.34$$

Since there is sudden rise in current at the last observation, this is used to evaluate  $\gamma$ . We know that

or 
$$I = \frac{I_0 e^{\alpha x}}{1 - \gamma (e^{\alpha x} - 1)}$$
or 
$$\frac{I}{I_0} = \frac{7}{6} \times 10^7 = \frac{e^{26.34 \times 0.5}}{1 - \gamma (e^{13.17} - 1)}$$

$$= \frac{5.24 \times 10^5}{1 - 5.24 \times 10^5 \gamma}$$
or 
$$\frac{7}{6} \times 10^7 \frac{1}{5.24 \times 10^5} = \frac{1}{1 - 5.24 \times 10^5 \gamma}$$
or 
$$0.0449 = 1 - 5.24 \times 10^5 \gamma$$
or 
$$0.9551 = 5.24 \times 10^5 \gamma$$
or 
$$\gamma = 0.182 \times 10^{-5} / \text{cm}$$

Set-II. For the same gap distance the slope will be  $\alpha = \ln (12/8)/0.05 = 8.1$  collisions/cm and therefore

$$\frac{I}{I_0} = 2 \times 10^5 = \frac{e^{8.1 \times 0.5}}{1 - \gamma (e^{4.05} - 1)}$$
$$2 \times 10^5 = \frac{57.39}{1 - \gamma (56.39)}$$

or 
$$\frac{200 \times 10^3}{57.39} = 3.4849 \times 10^3 = \frac{1}{1 - 56.39\gamma}$$
$$2.87 \times 10^{-4} = 1 - 56.39 \gamma$$

$$56.39\gamma = 1.0$$
 or 
$$\gamma = 1.7 \times 10^{-2} \text{ collisions/cm}$$